



National Accreditation Board for Testing and Calibration Laboratories

(A Constituent Board of Quality Council of India)



SCOPE OF ACCREDITATION

SAMEER KOLKATA CENTRE, R & D LABORATORY, MINISTRY OF ELECTRONICS AND INFORMATION TECHNOLOGY, GOVT. OF INDIA, PLOT - L2, BLOCK - GP, SALT LAKE ELECTRONICS COMPLEX, SECTOR - V, SALT LAKE, KOLKATA, WEST BENGAL, INDIA **Laboratory Name**

Accreditation Standard ISO/IEC 17025:2005

TC-8298 Page No.: 1/2 Certificate Number

Validity 18/01/2019 to 17/01/2021 Last Amended on

| S.No | Discipline / Group | Product / Material of Test | Specific Test Performed | Test Method Specification against which tests are performed | Range of Testing/ Limits of Detection |
|------|-----------------------------------|-----------------------------------|---|--|--|
| | | Pe | rmanent Facility | | |
| 1 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Conducted Emission | CISPR 32 (edition 2.0): 2015 | 150 kHz to 30 MHz |
| 2 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Conducted Emission | CISPR 14-1 (edition 6.0): 2016 | 150 kHz to 30 MHz |
| 3 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Conducted Emission | CISPR 11 (edition 6.0): 2015 | 150 kHz to 30 MHz |
| 4 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Electrical fast transient / burst immunity test | IEC 61000-4-4 (edition 3.0): 2012 | Qualitative(Upto +/- 4 kV) |
| 5 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Electrostatic Discharge Immunity Test | IEC 61000-4-2 (edition 2.0): 2008 | Qualitative(Upto +/- 8 kV in Contact Discharge and Upto +/- 15 kV in Air Discharge) |
| 6 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Immunity to conducted disturbance induced by radio-frequency fields | IEC 61000-4-6 (edition 4): 2013 | 150 kHz to 80 MHz |
| 7 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Power frequency magnetic field immunity test | IEC 61000-4-8 (edition 2.0): 2009 | 1 A/m to 100 A/m |
| 8 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Radiated Emission | CISPR 11 (edition 6.0): 2015 | 30 MHz to 6 GHz |
| 9 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Radiated Emission | CISPR 32 (edition 2.0): 2015 | 30 MHz to 6 GHz |
| 10 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Radiated Emission | CISPR 14-1 (edition 6.0): 2016 | 30 MHz to 1 GHz |





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'In view of the transition deadline for ISO/IEC 17025:2017, the validity of this accreditation certificate will cease on 30.11.2020.'

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|------|-----------------------------------|--------------------------------------|--|--|--|
| 11 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Radiated, radio- frequency, electromagnetic field immunity test | IEC 61000-4-3 (edition 3.2): 2010 | 80 MHz to 6 GHz |
| 12 | ELECTRONICS- EMC TEST FACILITY | Electrical and Electronic product | Surge immunity test | IEC 61000-4-5 (edition 3.0): 2017 | Qualitative(Upto +/- 4 kV) |